

IGBT Chip in NPT-technology

FEATURES:

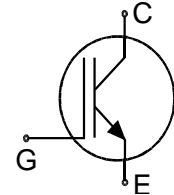
- 1200V NPT technology
- 180µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

- SGP02N120

Applications:

- drives, SMPS, resonant applications



Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC06T120CS	1200V	2A	2.45 x 2.25 mm ²	sawn on foil	Q67050-A4115-A001

MECHANICAL PARAMETER:

Raster size	2.45 x 2.25	mm ²
Area total / active	5.512 / 2.5	
Emitter pad size	1.03x1.29	
Gate pad size	0.42x0.56	
Thickness	180	µm
Wafer size	150	mm
Flat position	0	deg
Max.possible chips per wafer	2794 pcs	
Passivation frontside	Photoimide	
Emitter metalization	3200 nm Al Si 1%	
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding	
Die bond	electrically conductive glue or solder	
Wire bond	Al, ≤500µm	
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm	
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month	

MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	1200	V
DC collector current, limited by T_{jmax}	I_C	2	A
Pulsed collector current, t_p limited by T_{jmax}	I_{Cpuls}	4	A
Gate emitter voltage	V_{GE}	± 20	V
Operating junction and storage temperature	T_j, T_{stg}	-55 ... +150	$^{\circ}C$

STATIC CHARACTERISTICS (tested on chip), $T_j=25^{\circ}C$, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=300\mu A$	1200			V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=2A$	2.5	3.1	3.6	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=90\mu A, V_{GE}=V_{CE}$	3.0	4.0	5.0	
Zero gate voltage collector current	I_{CES}	$V_{CE}=1200V, V_{GE}=0V$			10	μA
Gate-emitter leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=30V$			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

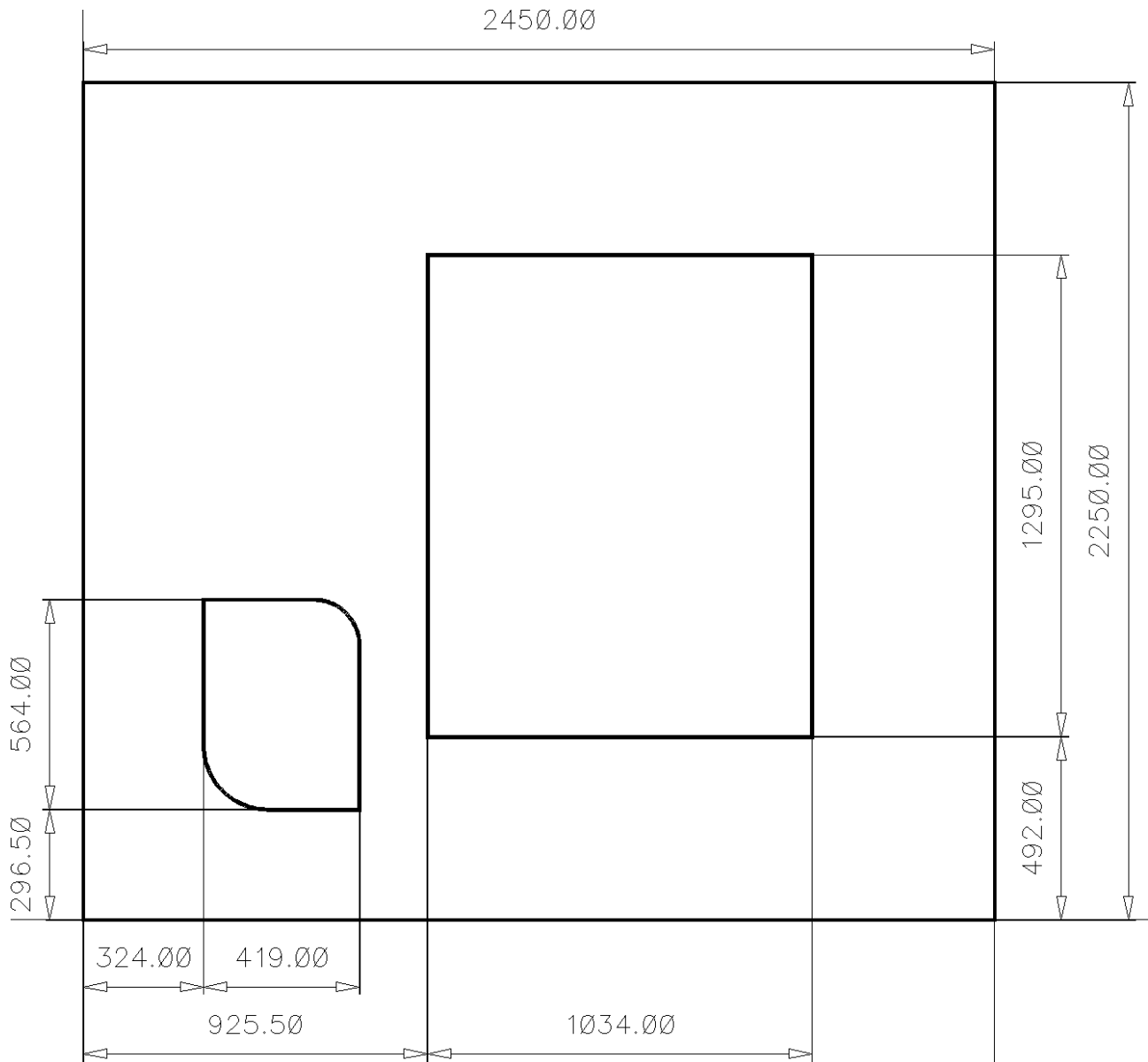
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Input capacitance	C_{iss}	$V_{CE}=25V,$	-	205	250	pF
Output capacitance	C_{oss}	$V_{GE}=0V,$	-	28	34	
Reverse transfer capacitance	C_{riss}	$f=1MHz$	-	17	21	

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions*	Value			Unit
			min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	$T_j=25^{\circ}C$ $V_{CC}=800V,$ $I_C=2A$ $V_{GE}=+15/0V,$ $R_G=91\Omega$	-	23	30	ns
Rise time	t_r		-	16	21	
Turn-off delay time	$t_{d(off)}$		-	260	340	
Fall time	t_f		-	61	80	

* switching conditions different to LowLoss, Standard, IGBT3; under comparable switching conditions 40% faster than Standard

CHIP DRAWING:





Preliminary

SIGC06T120CS

FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

SGP02N120

Package : TO220

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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